

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/597,407	TAKUMAI, SUSUMU	
Examiner		Art Unit		Page 1 of 1
DEVONA E. FAULK		2614		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2006/0153391	07-2006	Hooley et al.	381/017
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	JP 2005064746 A	03-2005	Japan	SAWABEI et al.	H04S 5/02
*	O	JP 2003299180 A	10-2003	Japan	SAN et al.	H04S 3/00
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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